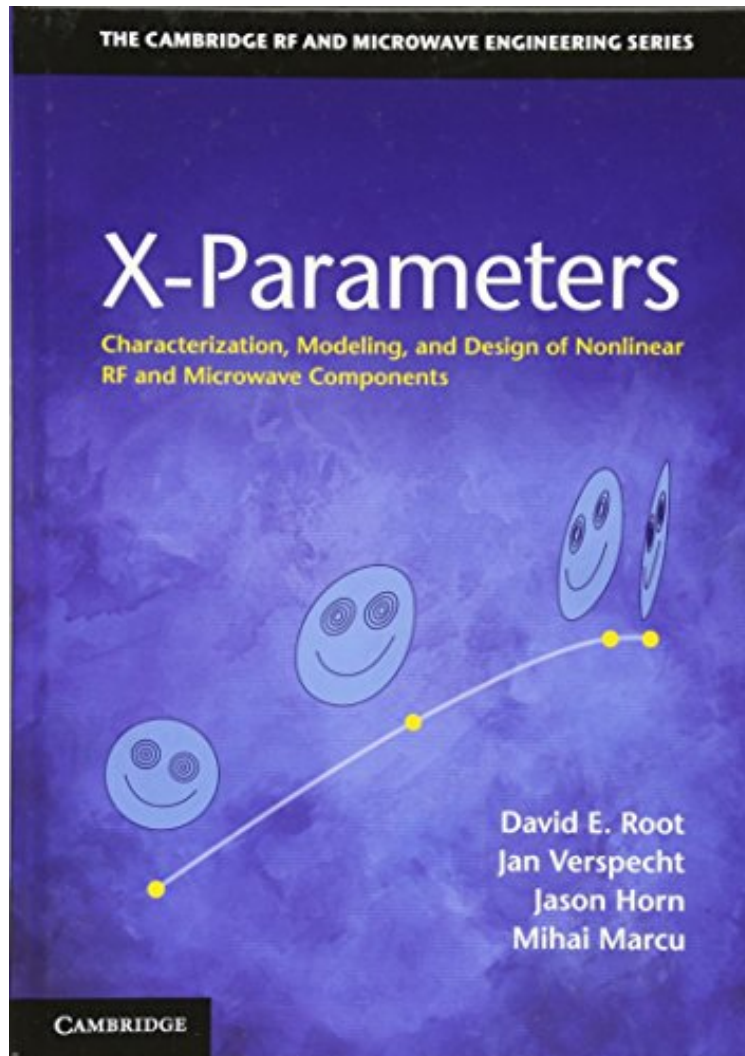


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X-Parameters: Characterization, Modeling, and Design of Nonlinear RF and Microwave Components (The Cambridge RF and Microwave Engineering Series)

David E. Root, Jan Verspecht, Jason Horn, Mihai Marcu
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About the Author
David E. Root is an Agilent Research Fellow at Agilent Technologies. He co-led the Agilent research and technical development of X-parameters through its commercialization. He is a Fellow of the IEEE and co-editor of Nonlinear Transistor Model Parameter Extraction Techniques (2011).
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